

Application/Control No.	Applicant(s)/Patent under Reexamination
10/667,675	ANIKITCHEV ET AL.
Examiner	Art Unit
lim Vannucci	2828

	SEARCHED				
Class	Subclass	Date	Examiner		
372	101	7/8/2005	٦V		
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
laser, diode, array	7/8/2005	JV